

# Self-test

Fill out the table in the next slide.

Central column: for each scanning probe technique indicate what property is measured, registered and shown in the output.

Right column: specify the parameter that is maintained constant throughout the measurement.

Choose right answers from the list below (for each columns).

Note that:

-in some cases more than one item from the list may be acceptable

-some listed items may be acceptable for more than one technique (or not acceptable at all)

## Variants of answers :

- (1) DC voltage
- (2) Cantilever deflection
- (3) Scanner height (z)
- (4) AC voltage
- (5) Current
- (6) Indentation depth
- (7) Amplitude of cantilever oscillation
- (8) Reflectivity of cantilever
- (9) Tip-surface capacitance
- (10) Distance between probe tip and sample
- (11) amplitude of oscillation of the cantilever

	Property that is measured and registered for the output	Parameter that is kept constant throughout the measurement
Contact atomic force microscopy (AFM) (constant force mode)		
Tapping (intermittent) mode atomic force microscopy		
Kelvin probe microscopy (KPM)		
Magnetic force microscopy (MFM)		
Conductive atomic force microscopy		
PFM		